

FQP11N40C/FQPF11N40C 400V N-Channel MOSFET

Features

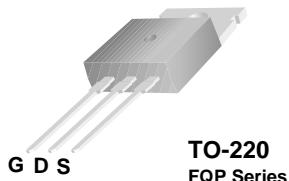
- 10.5 A, 400V, $R_{DS(on)} = 0.5 \Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 28 nC)
- Low C_{rss} (typical 85pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability



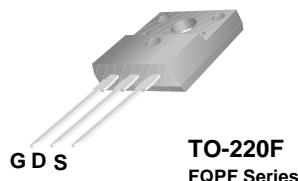
Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

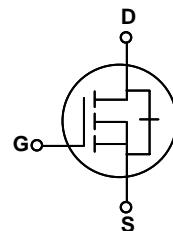
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.



TO-220
FQP Series



TO-220F
FQPF Series



Absolute Maximum Ratings

Symbol	Parameter	FQP11N40C	FQPF11N40C	Units	
V_{DSS}	Drain-Source Voltage	400		V	
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	10.5	10.5 *	A	
	- Continuous ($T_C = 100^\circ\text{C}$)	6.6	6.6 *	A	
I_{DM}	Drain Current - Pulsed	(Note 1)	42	42 *	A
V_{GSS}	Gate-Source Voltage		± 30	V	
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	360	mJ	
I_{AR}	Avalanche Current	(Note 1)	11	A	
E_{AR}	Repetitive Avalanche Energy	(Note 1)	13.5	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	135	44	W	
	- Derate above 25°C	1.07	0.35	W/ $^\circ\text{C}$	
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$	
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	$^\circ\text{C}$	

* Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQP11N40C	FQPF11N40C	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.93	2.86	$^\circ\text{C}/\text{W}$
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	--	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	$^\circ\text{C}/\text{W}$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP11N40C	FQP11N40C	TO-220	--	--	50
FQPF11N40C	FQPF11N40C	TO-220F	--	--	50

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units	
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	400	--	--	V	
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	--	0.54	--	$\text{V}/^\circ\text{C}$	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 400 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$	--	--	1	μA	
		$V_{\text{DS}} = 320 \text{ V}$, $T_C = 125^\circ\text{C}$	--	--	10	μA	
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA	
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA	
On Characteristics							
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250 \mu\text{A}$	2.0	--	4.0	V	
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10 \text{ V}$, $I_D = 5.25 \text{ A}$	--	0.43	0.53	Ω	
g_{FS}	Forward Transconductance	$V_{\text{DS}} = 40 \text{ V}$, $I_D = 5.25 \text{ A}$	(Note 4)	--	7.1	--	
Dynamic Characteristics							
C_{iss}	Input Capacitance	$V_{\text{DS}} = 25 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$	--	840	1090	pF	
C_{oss}	Output Capacitance		--	250	325	pF	
C_{rss}	Reverse Transfer Capacitance		--	85	110	pF	
Switching Characteristics							
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 200 \text{ V}$, $I_D = 10.5 \text{ A}$, $R_G = 25 \Omega$	--	14	40	ns	
t_r	Turn-On Rise Time		--	89	190	ns	
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	81	170	ns	
t_f	Turn-Off Fall Time		--	81	170	ns	
Q_g	Total Gate Charge	$V_{\text{DS}} = 320 \text{ V}$, $I_D = 10.5 \text{ A}$, $V_{\text{GS}} = 10 \text{ V}$	--	28	35	nC	
Q_{gs}	Gate-Source Charge		--	4	--	nC	
Q_{gd}	Gate-Drain Charge		--	15	--	nC	
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	10.5	A		
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	42	A		
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_S = 10.5 \text{ A}$	--	--	1.4	V	
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0 \text{ V}$, $I_S = 10.5 \text{ A}$, $dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	290	--	ns	
Q_{rr}	Reverse Recovery Charge		(Note 4)	--	2.4	--	
Notes:							
1. Repetitive Rating : Pulse width limited by maximum junction temperature							
2. L = 5.7 mH, $I_{AS} = 10.5 \text{ A}$, $V_{DD} = 50 \text{ V}$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$							
3. $I_{SD} \leq 10.5 \text{ A}$, $dI/dt \leq 200 \text{ A}/\mu\text{s}$, $V_{DD} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$							
4. Pulse Test : Pulse width $\leq 300 \mu\text{s}$, Duty cycle $\leq 2\%$							
5. Essentially independent of operating temperature							

Typical Performance Characteristics

Figure 1. On-Region Characteristics

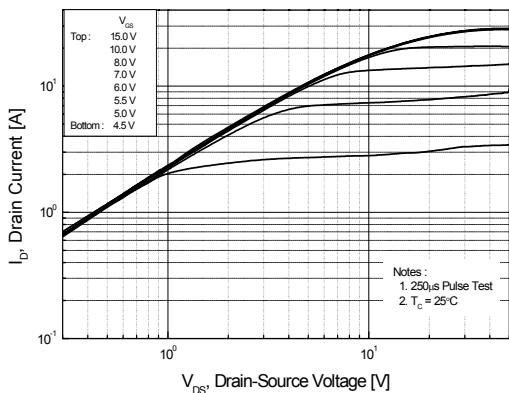


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

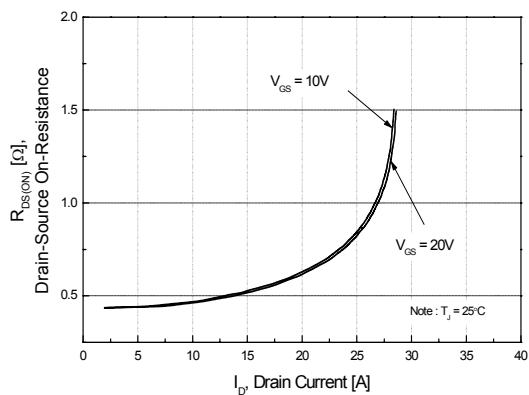


Figure 5. Capacitance Characteristics

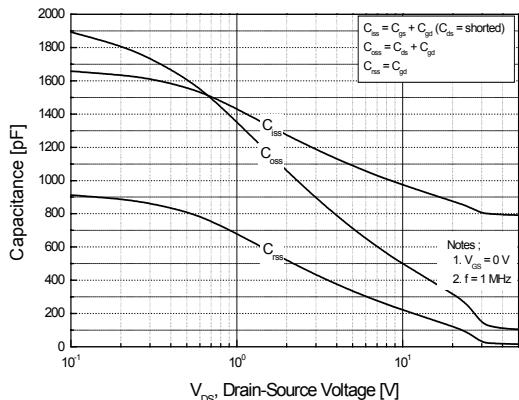


Figure 2. Transfer Characteristics

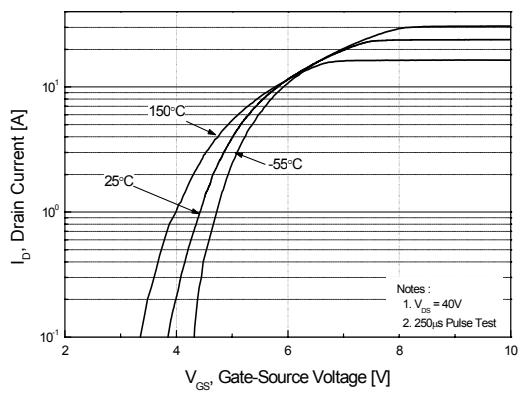


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

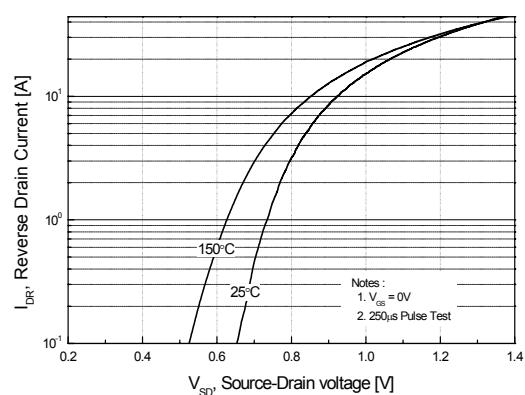
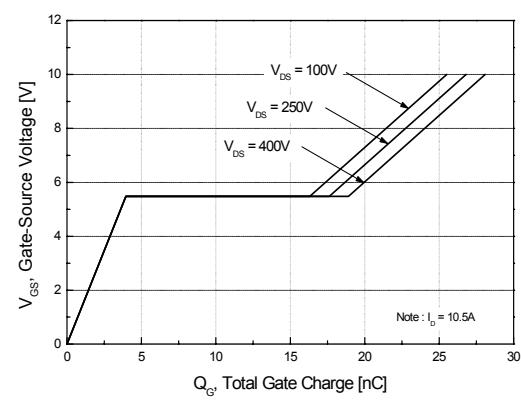


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

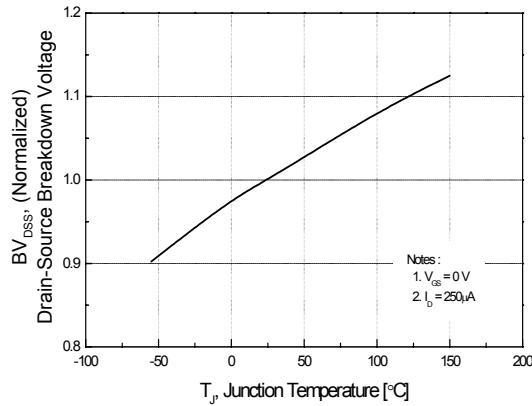


Figure 8. On-Resistance Variation vs. Temperature

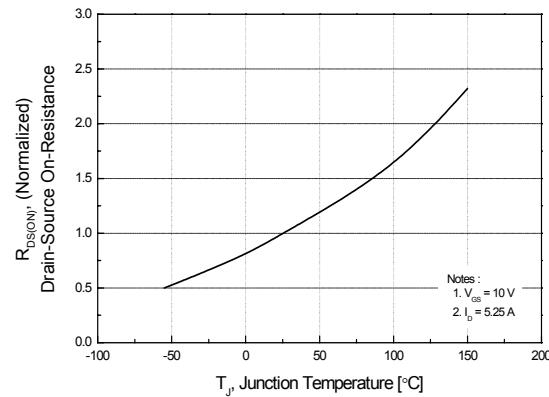


Figure 9-1. Maximum Safe Operating Area of FQP11N40C

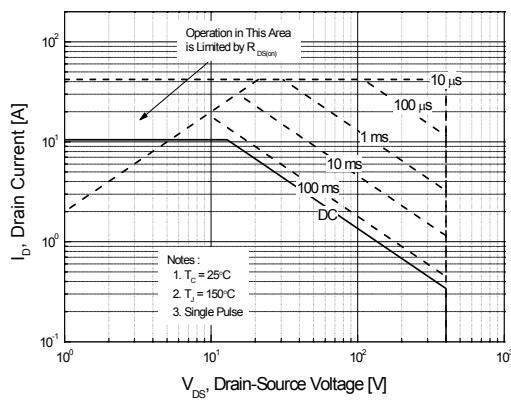


Figure 9-2. Maximum Safe Operating Area of FQPF11N40C

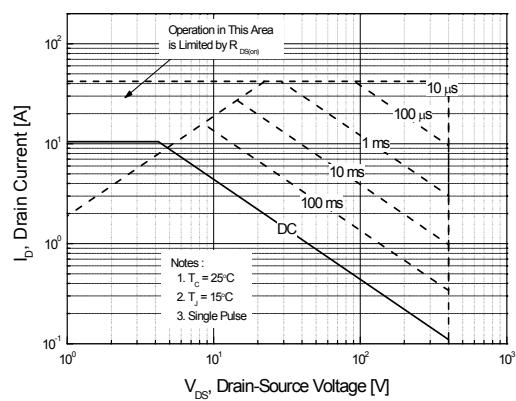
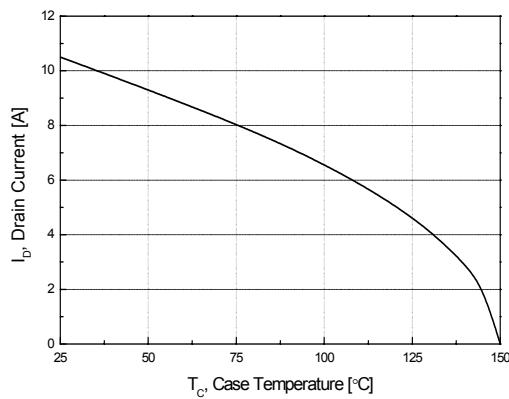


Figure 10. Maximum Drain Current



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve of FQP11N40C

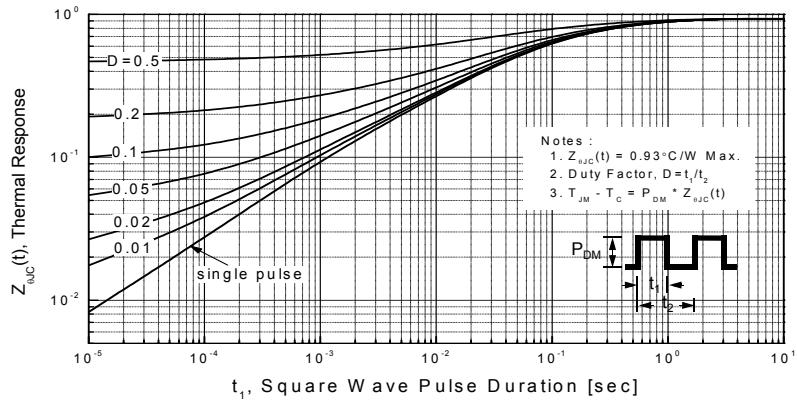
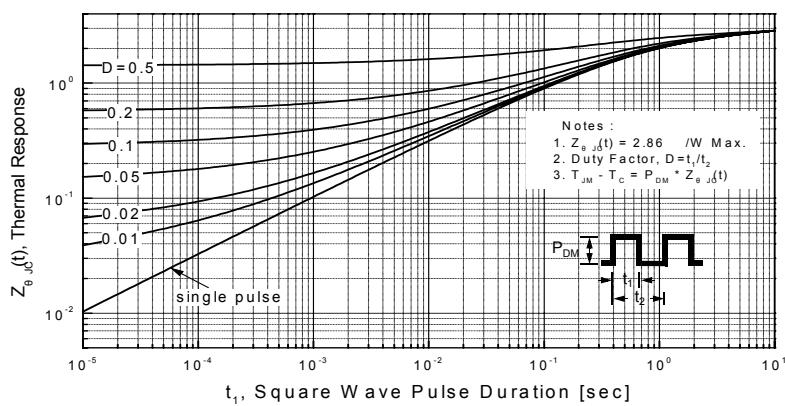
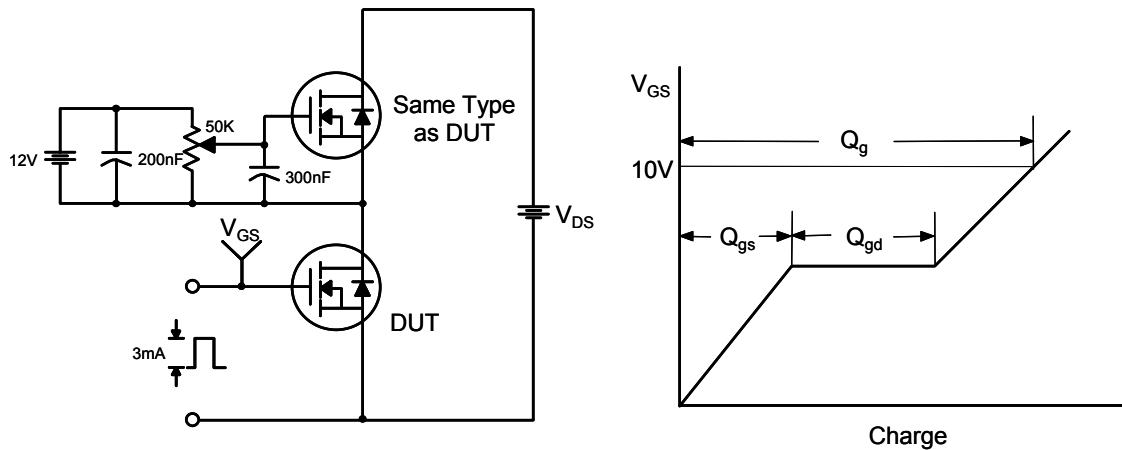


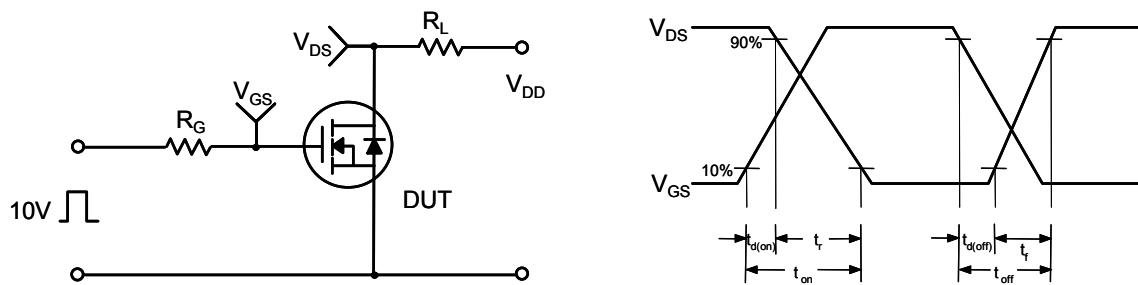
Figure 11-2. Transient Thermal Response Curve of FQPF11N40C



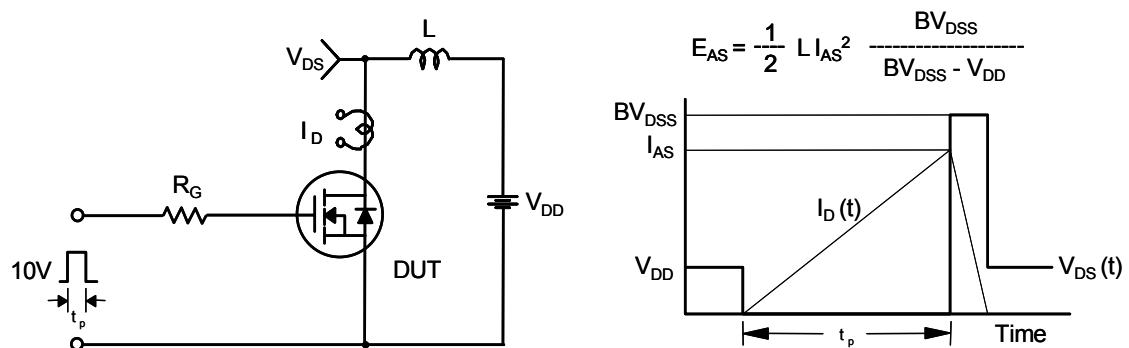
Gate Charge Test Circuit & Waveform



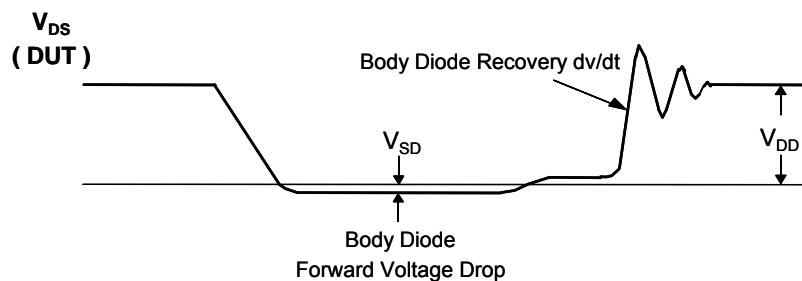
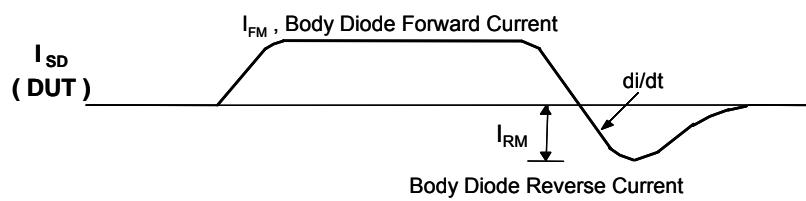
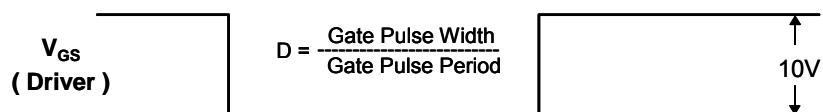
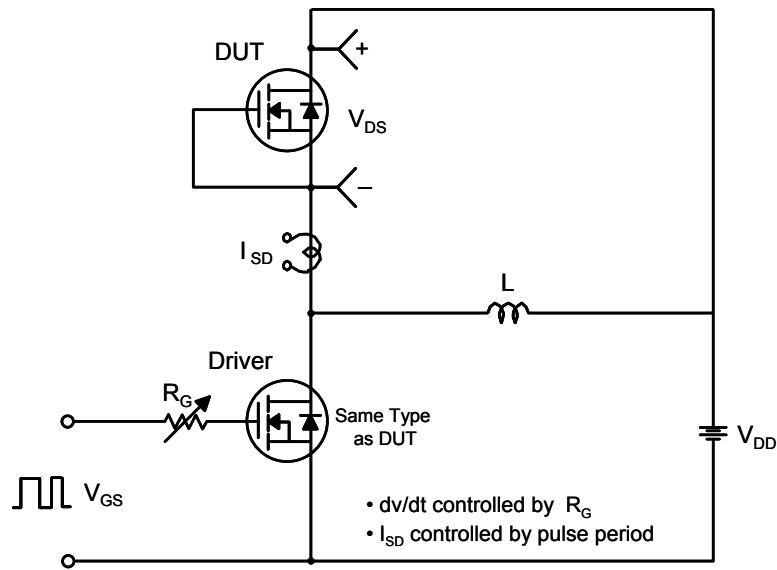
Resistive Switching Test Circuit & Waveforms

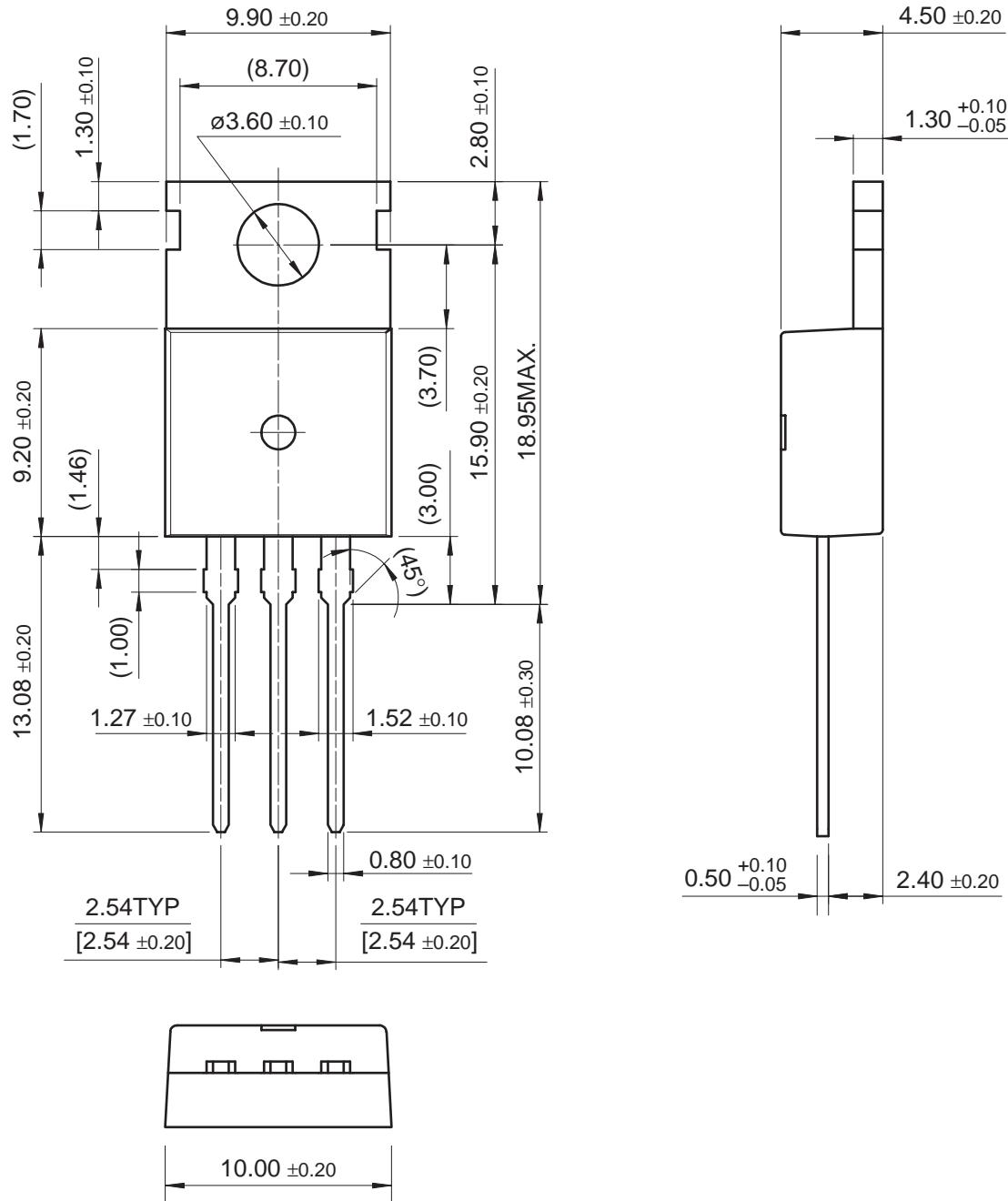


Unclamped Inductive Switching Test Circuit & Waveforms

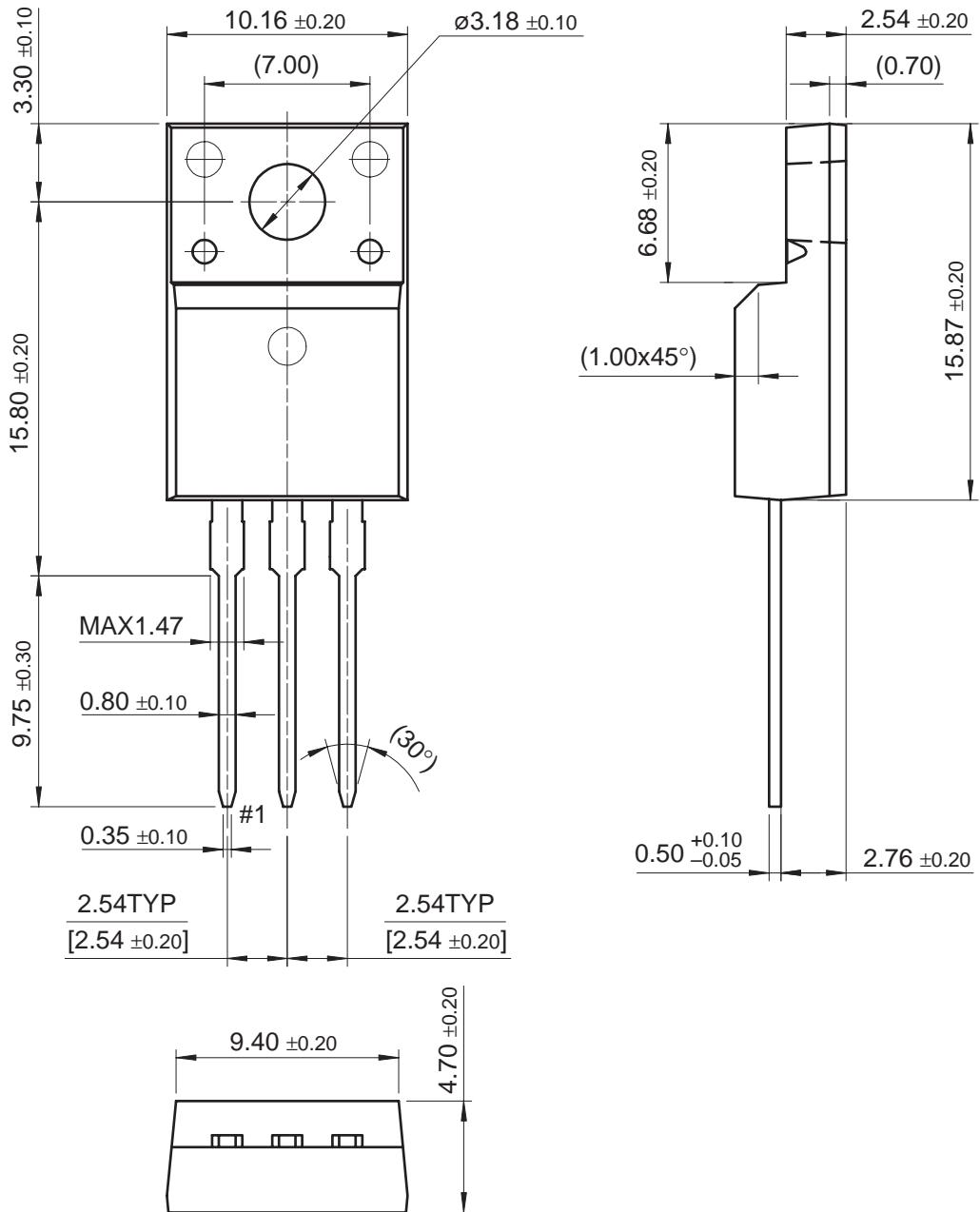


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions**TO-220**

Dimensions in Millimeters

Mechanical Dimensions (Continued)**TO-220F**

Dimensions in Millimeters



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Rev. I34



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